



## Getting the most value out of your test data?

- Struggling with **scattered test data**?
- Waiting time on test data in **different formats** from different test stations?
- Not getting the information you need to **control your production**?

## Make Informed Decisions based on FACTS!

FACTS by CIM.AS imports your test data, consolidates them in a database and gives you instant and easy access through its friendly, web-based user interface. The analysis reports provide quick overviews of key production performance and product quality indicators, e.g. **Cp, Cpk, Mean, Distribution** etc, and enable you to focus your efforts where it really matters.

### Data Management

- Automated Collection, organization and storage of test data
- Optimized database design for fastest access.
- Multiple file formats supported

### Powerful Reporting

- Yield Reports
- Six Sigma Parameters
- Online UUT Test Reports
- Error Pareto
- Test Duration
- Waveform Data Statistics

### Advanced Filtering

- Get to the root cause by grouping your data, e.g. by
  - Test Station
  - Fixture
  - Firmware version
  - Operator

**Office Addresses:**













CIM A/S  
Jegstrupvej 96A  
8361 Hasselager  
Denmark

CIM A/S  
Ager Allé 3  
2970 Hørsholm  
Denmark

CIM A/S  
Storegade 82  
6430 Nordborg  
Denmark

**Administration Address:**

CIM A/S  
Fælledvej 17  
7600 Struer  
Denmark

	<b>SPC</b> Statistical analysis result for test steps, represented by mean value, standard deviation ( $\sigma$ ), Cp and Cpk index values as well as specification limits.		<b>Test Yield</b> Numeric details and bar-graph of the yield for a number of selected tests. Each bar in the graph shows the passed/failed relation of the performed tests.
	<b>Time Series</b> Time based XY-graph and the normal distribution graph of the measurements for a specific test step. Statistical analysis values are shown for the selected measurements.		<b>Test Step Yield</b> Numeric details and graphical presentation of the yield for each individual test step for a selected test. The combined bar-graph shows test steps and their yield.
	<b>Test Result</b> Provides an overview in list form of tests performed in the production.		<b>Test Step Error Pareto</b> Sorted list of most frequent failed test steps for a selected item.
	<b>Unit Overview</b> Test step result and measurements for all performed test runs for a specific item serial number.		<b>Test Duration</b> Time based stacked bar-graph showing the relation between the total test and handling time for selected tests. The number of tests performed is shown in a separate XY-line.
	<b>Unit</b> Detailed report for a specific unit that includes all the information known to the system.		<b>Test Step Duration</b> Detailed duration information for all test steps in a test.
	<b>Repair Pareto</b> Chart and sorted list of most frequent repairs entered via the Paperless Repair application.		<b>XY Graph</b> Visualize numeric array step results in XY chart.

**Standard Reports**

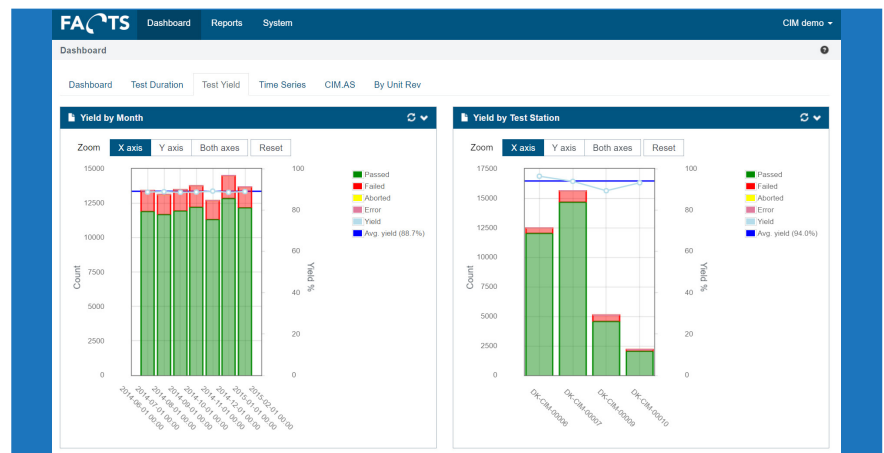
Export to .pdf and Excel

**Custom Reports**

Can be developed and integrated according to your business needs

**Custom Reports**

Extract the test report from a unique serial number



**Custom Dashboard**

Create a dashboard with your key business data

**Search sharing**

Full URL for easy share of searches

**Kiosk Mode**

Automated presentation of your most important data

**CIM meets the challenge**

We cover the value chain from R&D and throughout the production – no matter if it is local, global or EMS.

**Visit CIM.AS**

- Access FACTS demo site
- Download user guide
- Read Use cases
- Request further information